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### What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

### Applications of "[Embedded - Microcontrollers](#)"

#### Details

Product Status	Not For New Designs
Core Processor	R8C
Core Size	16-Bit
Speed	20MHz
Connectivity	I <sup>2</sup> C, LINbus, SIO, SSU, UART/USART
Peripherals	LED, POR, Voltage Detect, WDT
Number of I/O	13
Program Memory Size	8KB (8K x 8)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	512 x 8
Voltage - Supply (Vcc/Vdd)	2.2V ~ 5.5V
Data Converters	A/D 4x10b
Oscillator Type	Internal
Operating Temperature	-20°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	20-LSSOP (0.173", 4.40mm Width)
Supplier Device Package	20-LSSOP
Purchase URL	<a href="https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f21292snsp-u0">https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f21292snsp-u0</a>

**Table 1.2 Functions and Specifications for R8C/29 Group**

Item		Specification
CPU	Number of fundamental instructions	89 instructions
	Minimum instruction execution time	50 ns ( $f(XIN) = 20$ MHz, $VCC = 3.0$ to $5.5$ V) (other than K version) 62.5 ns ( $f(XIN) = 16$ MHz, $VCC = 3.0$ to $5.5$ V) (K version) 100 ns ( $f(XIN) = 10$ MHz, $VCC = 2.7$ to $5.5$ V) 200 ns ( $f(XIN) = 5$ MHz, $VCC = 2.2$ to $5.5$ V) (N, D version)
	Operating mode	Single-chip
	Address space	1 Mbyte
	Memory capacity	Refer to <b>Table 1.4 Product Information for R8C/29 Group</b>
Peripheral Functions	Ports	I/O ports: 13 pins, Input port: 3 pins
	LED drive ports	I/O ports: 8 pins (N, D version)
	Timers	Timer RA: 8 bits $\times$ 1 channel Timer RB: 8 bits $\times$ 1 channel (Each timer equipped with 8-bit prescaler) Timer RC: 16 bits $\times$ 1 channel (Input capture and output compare circuits) Timer RE: With real-time clock and compare match function (For J, K version, compare match function only.)
	Serial interfaces	1 channel (UART0): Clock synchronous serial I/O, UART 1 channel (UART1): UART
	Clock synchronous serial interface	1 channel I <sup>2</sup> C bus Interface <sup>(1)</sup> Clock synchronous serial I/O with chip select
	LIN module	Hardware LIN: 1 channel (timer RA, UART0)
	A/D converter	10-bit A/D converter: 1 circuit, 4 channels
	Watchdog timer	15 bits $\times$ 1 channel (with prescaler) Reset start selectable
	Interrupts	Internal: 15 sources (N, D version), Internal: 14 sources (J, K version) External: 4 sources, Software: 4 sources, Priority levels: 7 levels
	Clock generation circuits	3 circuits • XIN clock generation circuit (with on-chip feedback resistor) • On-chip oscillator (high speed, low speed) High-speed on-chip oscillator has a frequency adjustment function • XCIN clock generation circuit (32 kHz) (N, D version) • Real-time clock (timer RE) (N, D version)
	Oscillation stop detection function	XIN clock oscillation stop detection function
	Voltage detection circuit	On-chip
	Power-on reset circuit	On-chip
Electrical Characteristics	Supply voltage	$VCC = 3.0$ to $5.5$ V ( $f(XIN) = 20$ MHz) (other than K version) $VCC = 3.0$ to $5.5$ V ( $f(XIN) = 16$ MHz) (K version) $VCC = 2.7$ to $5.5$ V ( $f(XIN) = 10$ MHz) $VCC = 2.2$ to $5.5$ V ( $f(XIN) = 5$ MHz) (N, D version)
	Current consumption (N, D version)	Typ. 10 mA ( $VCC = 5.0$ V, $f(XIN) = 20$ MHz) Typ. 6 mA ( $VCC = 3.0$ V, $f(XIN) = 10$ MHz) Typ. 2.0 $\mu$ A ( $VCC = 3.0$ V, wait mode ( $f(XCIN) = 32$ kHz)) Typ. 0.7 $\mu$ A ( $VCC = 3.0$ V, stop mode)
Flash Memory	Programming and erasure voltage	$VCC = 2.7$ to $5.5$ V
	Programming and erasure endurance	10,000 times (data flash) 1,000 times (program ROM)
Operating Ambient Temperature		-20 to 85°C (N version) -40 to 85°C (D, J version) <sup>(2)</sup> , -40 to 125°C (K version) <sup>(2)</sup>
Package		20-pin molded-plastic LSSOP

## NOTES:

1. I<sup>2</sup>C bus is a trademark of Koninklijke Philips Electronics N. V.
2. Specify the D, K version if D, K version functions are to be used.

## 1.6 Pin Functions

Table 1.5 lists Pin Functions.

**Table 1.5 Pin Functions**

Type	Symbol	I/O Type	Description
Power supply input	VCC, VSS	I	Apply 2.2 to 5.5 V (J, K version are 2.7 to 5.5 V) to the VCC pin. Apply 0 V to the VSS pin.
Analog power supply input	AVCC, AVSS	I	Power supply for the A/D converter. Connect a capacitor between AVCC and AVSS.
Reset input	$\overline{\text{RESET}}$	I	Input "L" on this pin resets the MCU.
MODE	MODE	I	Connect this pin to VCC via a resistor.
XIN clock input	XIN	I	These pins are provided for XIN clock generation circuit I/O. Connect a ceramic resonator or a crystal oscillator between the XIN and XOUT pins. To use an external clock, input it to the XIN pin and leave the XOUT pin open.
XIN clock output	XOUT	O	
XCIN clock input (N, D version)	XCIN	I	These pins are provided for XCIN clock generation circuit I/O. Connect a crystal oscillator between the XCIN and XCOU pins. To use an external clock, input it to the XCIN pin and leave the XCOU pin open.
XCIN clock output (N, D version)	XCOU	O	
$\overline{\text{INT}}$ interrupt input	$\overline{\text{INT0}}, \overline{\text{INT1}}, \overline{\text{INT3}}$	I	$\overline{\text{INT}}$ interrupt input pins
Key input interrupt	$\overline{\text{KI0}}$ to $\overline{\text{KI3}}$	I	Key input interrupt input pins
Timer RA	TRA0	O	Timer RA output pin
	TRAIO	I/O	Timer RA I/O pin
Timer RB	TRBO	O	Timer RB output pin
Timer RC	TRCLK	I	External clock input pin
	TRCTR	I	External trigger input pin
	TRCIOA, TRCIOB, TRCIO, TRCIOD	I/O	Sharing output-compare output / input-capture input / PWM / PWM2 output pins
Serial interface	CLK0	I/O	Clock I/O pin
	RXD0, RXD1	I	Receive data input pin
	TXD0, TXD1	O	Transmit data output pin
I <sup>2</sup> C bus interface	SCL	I/O	Clock I/O pin
	SDA	I/O	Data I/O pin
Clock synchronous serial I/O with chip select	SSI	I/O	Data I/O pin
	$\overline{\text{SCS}}$	I/O	Chip-select signal I/O pin
	SSCK	I/O	Clock I/O pin
	SSO	I/O	Data I/O pin
Reference voltage input	VREF	I	Reference voltage input pin to A/D converter
A/D converter	AN8 to AN11	I	Analog input pins to A/D converter
I/O port	P1_0 to P1_7, P3_3 to P3_5, P3_7, P4_5	I/O	CMOS I/O ports. Each port has an I/O select direction register, allowing each pin in the port to be directed for input or output individually. Any port set to input can be set to use a pull-up resistor or not by a program. P1_0 to P1_7 also function as LED drive ports (N, D version).
Input port	P4_2, P4_6, P4_7	I	Input-only ports

I: Input      O: Output      I/O: Input and output

### 3. Memory

#### 3.1 R8C/28 Group

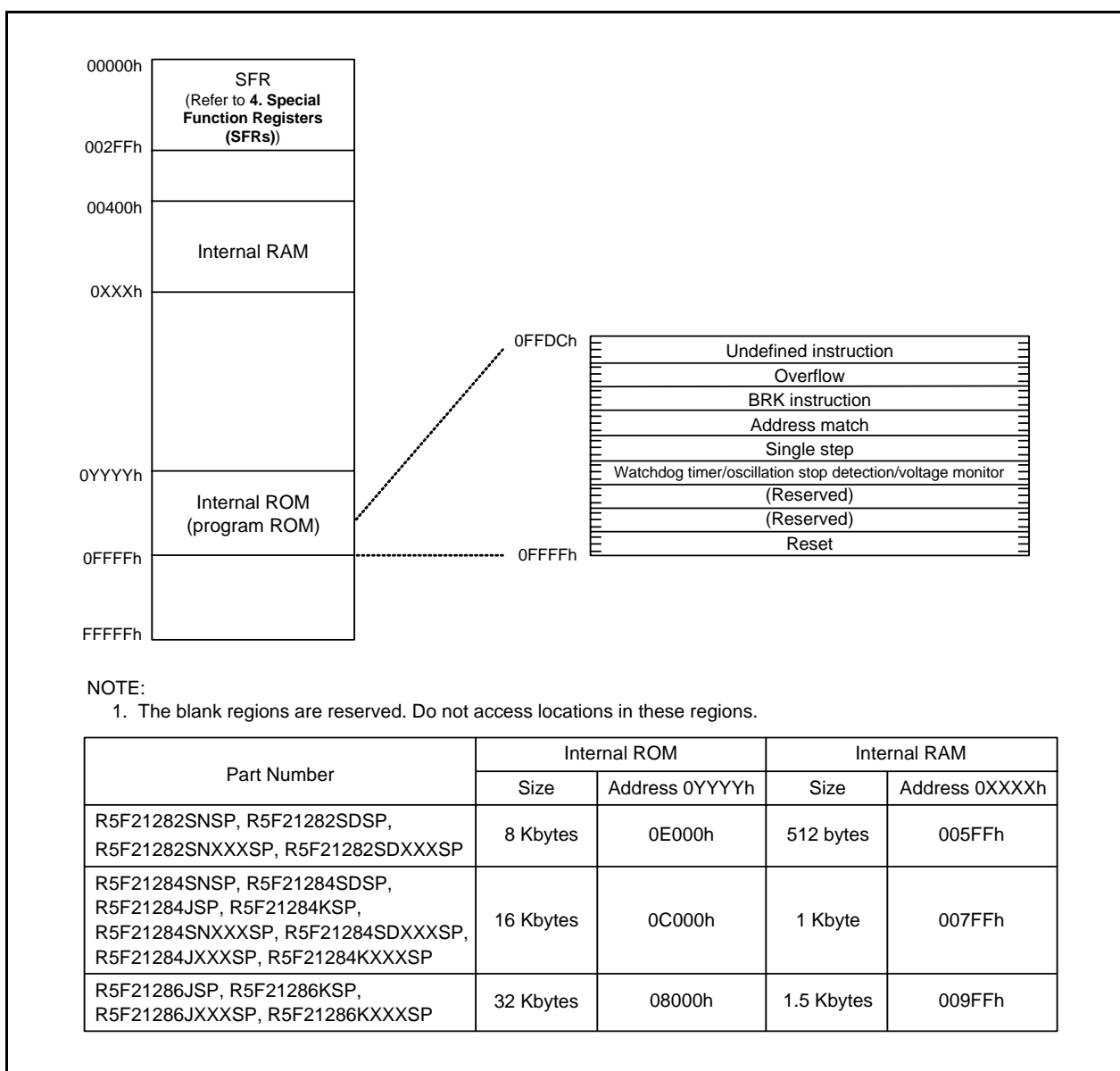
Figure 3.1 is a Memory Map of R8C/28 Group. The R8C/28 group has 1 Mbyte of address space from addresses 00000h to FFFFFh.

The internal ROM is allocated lower addresses, beginning with address 0FFFFh. For example, a 16-Kbyte internal ROM area is allocated addresses 0C000h to 0FFFFh.

The fixed interrupt vector table is allocated addresses 0FFDCh to 0FFFFh. They store the starting address of each interrupt routine.

The internal RAM is allocated higher addresses, beginning with address 00400h. For example, a 1-Kbyte internal RAM area is allocated addresses 00400h to 007FFh. The internal RAM is used not only for storing data but also for calling subroutines and as stacks when interrupt requests are acknowledged.

Special function registers (SFRs) are allocated addresses 00000h to 002FFh. The peripheral function control registers are allocated here. All addresses within the SFR, which have nothing allocated are reserved for future use and cannot be accessed by users.



**Figure 3.1 Memory Map of R8C/28 Group**

**Table 4.3 SFR Information (3)<sup>(1)</sup>**

Address	Register	Symbol	After reset
0080h			
0081h			
0082h			
0083h			
0084h			
0085h			
0086h			
0087h			
0088h			
0089h			
008Ah			
008Bh			
008Ch			
008Dh			
008Eh			
008Fh			
0090h			
0091h			
0092h			
0093h			
0094h			
0095h			
0096h			
0097h			
0098h			
0099h			
009Ah			
009Bh			
009Ch			
009Dh			
009Eh			
009Fh			
00A0h	UART0 Transmit/Receive Mode Register	U0MR	00h
00A1h	UART0 Bit Rate Register	U0BRG	XXh
00A2h	UART0 Transmit Buffer Register	U0TB	XXh
00A3h			XXh
00A4h	UART0 Transmit/Receive Control Register 0	U0C0	00001000b
00A5h	UART0 Transmit/Receive Control Register 1	U0C1	00000010b
00A6h	UART0 Receive Buffer Register	U0RB	XXh
00A7h			XXh
00A8h	UART1 Transmit/Receive Mode Register	U1MR	00h
00A9h	UART1 Bit Rate Register	U1BRG	XXh
00AAh	UART1 Transmit Buffer Register	U1TB	XXh
00ABh			XXh
00ACh	UART1 Transmit/Receive Control Register 0	U1C0	00001000b
00ADh	UART1 Transmit/Receive Control Register 1	U1C1	00000010b
00AEh	UART1 Receive Buffer Register	U1RB	XXh
00AFh			XXh
00B0h			
00B1h			
00B2h			
00B3h			
00B4h			
00B5h			
00B6h			
00B7h			
00B8h	SS Control Register H / IIC bus Control Register 1 <sup>(2)</sup>	SSCRH / ICCR1	00h
00B9h	SS Control Register L / IIC bus Control Register 2 <sup>(2)</sup>	SSCRL / ICCR2	01111101b
00BAh	SS Mode Register / IIC bus Mode Register <sup>(2)</sup>	SSMR / ICMR	00011000b
00BBh	SS Enable Register / IIC bus Interrupt Enable Register <sup>(2)</sup>	SSER / ICIER	00h
00BCh	SS Status Register / IIC bus Status Register <sup>(2)</sup>	SSSR / ICSR	00h / 0000X000b
00BDh	SS Mode Register 2 / Slave Address Register <sup>(2)</sup>	SSMR2 / SAR	00h
00BEh	SS Transmit Data Register / IIC bus Transmit Data Register <sup>(2)</sup>	SSTDR / ICDRT	FFh
00BFh	SS Receive Data Register / IIC bus Receive Data Register <sup>(2)</sup>	SSRDR / ICDRR	FFh

X: Undefined

## NOTES:

1. The blank regions are reserved. Do not access locations in these regions.
2. Selected by the IICSEL bit in the PMR register.

**Table 4.6 SFR Information (6)<sup>(1)</sup>**

Address	Register	Symbol	After reset
0140h			
0141h			
0142h			
0143h			
0144h			
0145h			
0146h			
0147h			
0148h			
0149h			
014Ah			
014Bh			
014Ch			
014Dh			
014Eh			
014Fh			
0150h			
0151h			
0152h			
0153h			
0154h			
0155h			
0156h			
0157h			
0158h			
0159h			
015Ah			
015Bh			
015Ch			
015Dh			
015Eh			
015Fh			
0160h			
0161h			
0162h			
0163h			
0164h			
0165h			
0166h			
0167h			
0168h			
0169h			
016Ah			
016Bh			
016Ch			
016Dh			
016Eh			
016Fh			
0170h			
0171h			
0172h			
0173h			
0174h			
0175h			
0176h			
0177h			
0178h			
0179h			
017Ah			
017Bh			
017Ch			
017Dh			
017Eh			
017Fh			

NOTE:

1. The blank regions are reserved. Do not access locations in these regions.

**Table 5.5 Flash Memory (Data flash Block A, Block B) Electrical Characteristics<sup>(4)</sup>**

Symbol	Parameter	Conditions	Standard			Unit
			Min.	Typ.	Max.	
—	Program/erase endurance <sup>(2)</sup>		10,000 <sup>(3)</sup>	—	—	times
—	Byte program time (program/erase endurance ≤ 1,000 times)		—	50	400	μs
—	Byte program time (program/erase endurance > 1,000 times)		—	65	—	μs
—	Block erase time (program/erase endurance ≤ 1,000 times)		—	0.2	9	s
—	Block erase time (program/erase endurance > 1,000 times)		—	0.3	—	s
t <sub>d</sub> (SR-SUS)	Time delay from suspend request until suspend		—	—	97 + CPU clock × 6 cycles	μs
—	Interval from erase start/restart until following suspend request		650	—	—	μs
—	Interval from program start/restart until following suspend request		0	—	—	ns
—	Time from suspend until program/erase restart		—	—	3 + CPU clock × 4 cycles	μs
—	Program, erase voltage		2.7	—	5.5	V
—	Read voltage		2.2	—	5.5	V
—	Program, erase temperature		-20 <sup>(8)</sup>	—	85	°C
—	Data hold time <sup>(9)</sup>	Ambient temperature = 55°C	20	—	—	year

## NOTES:

1. V<sub>CC</sub> = 2.7 to 5.5 V at T<sub>opr</sub> = -20 to 85°C (N version) / -40 to 85°C (D version), unless otherwise specified.
2. Definition of programming/erasure endurance  
The programming and erasure endurance is defined on a per-block basis.  
If the programming and erasure endurance is n (n = 10,000), each block can be erased n times. For example, if 1,024 1-byte writes are performed to different addresses in block A, a 1 Kbyte block, and then the block is erased, the programming/erasure endurance still stands at one.  
However, the same address must not be programmed more than once per erase operation (overwriting prohibited).
3. Endurance to guarantee all electrical characteristics after program and erase. (1 to Min. value can be guaranteed).
4. Standard of block A and block B when program and erase endurance exceeds 1,000 times. Byte program time to 1,000 times is the same as that in program ROM.
5. In a system that executes multiple programming operations, the actual erasure count can be reduced by writing to sequential addresses in turn so that as much of the block as possible is used up before performing an erase operation. For example, when programming groups of 16 bytes, the effective number of rewrites can be minimized by programming up to 128 groups before erasing them all in one operation. In addition, averaging the erasure endurance between blocks A and B can further reduce the actual erasure endurance. It is also advisable to retain data on the erasure endurance of each block and limit the number of erase operations to a certain number.
6. If an error occurs during block erase, attempt to execute the clear status register command, then execute the block erase command at least three times until the erase error does not occur.
7. Customers desiring program/erase failure rate information should contact their Renesas technical support representative.
8. -40°C for D version.
9. The data hold time includes time that the power supply is off or the clock is not supplied.

**Table 5.10 High-speed On-Chip Oscillator Circuit Electrical Characteristics**

Symbol	Parameter	Condition	Standard			Unit
			Min.	Typ.	Max.	
fOCO40M	High-speed on-chip oscillator frequency temperature • supply voltage dependence	VCC = 4.75 to 5.25 V 0°C ≤ Topr ≤ 60°C <sup>(2)</sup>	39.2	40	40.8	MHz
		VCC = 3.0 to 5.5 V -20°C ≤ Topr ≤ 85°C <sup>(2)</sup>	38.8	40	41.2	MHz
		VCC = 3.0 to 5.5 V -40°C ≤ Topr ≤ 85°C <sup>(2)</sup>	38.4	40	41.6	MHz
		VCC = 2.7 to 5.5 V -20°C ≤ Topr ≤ 85°C <sup>(2)</sup>	38	40	42	MHz
		VCC = 2.7 to 5.5 V -40°C ≤ Topr ≤ 85°C <sup>(2)</sup>	37.6	40	42.4	MHz
		VCC = 2.2 to 5.5 V -20°C ≤ Topr ≤ 85°C <sup>(3)</sup>	35.2	40	44.8	MHz
		VCC = 2.2 to 5.5 V -40°C ≤ Topr ≤ 85°C <sup>(3)</sup>	34	40	46	MHz
		VCC = 5.0 V ± 10% -20°C ≤ Topr ≤ 85°C <sup>(2)</sup>	38.8	40	40.8	MHz
		VCC = 5.0 V ± 10% -40°C ≤ Topr ≤ 85°C <sup>(2)</sup>	38.4	40	40.8	MHz
	High-speed on-chip oscillator frequency when correction value in FRA7 register is written to FRA1 register <sup>(4)</sup>	VCC = 5.0 V, Topr = 25°C	—	36.864	—	MHz
		VCC = 3.0 to 5.5 V -20°C ≤ Topr ≤ 85°C	-3%	—	3%	%
—	Value in FRA1 register after reset		08h <sup>(3)</sup>	—	F7h <sup>(3)</sup>	—
—	Oscillation frequency adjustment unit of high-speed on-chip oscillator	Adjust FRA1 register (value after reset) to -1	—	+0.3	—	MHz
—	Oscillation stability time		—	10	100	μs
—	Self power consumption at oscillation	VCC = 5.0 V, Topr = 25°C	—	400	—	μA

## NOTES:

1. VCC = 2.2 to 5.5 V, Topr = -20 to 85°C (N version) / -40 to 85°C (D version), unless otherwise specified.
2. These standard values show when the FRA1 register value after reset is assumed.
3. These standard values show when the corrected value of the FRA6 register is written to the FRA1 register.
4. This enables the setting errors of bit rates such as 9600 bps and 38400 bps to be 0% when the serial interface is used in UART mode.

**Table 5.11 Low-speed On-Chip Oscillator Circuit Electrical Characteristics**

Symbol	Parameter	Condition	Standard			Unit
			Min.	Typ.	Max.	
fOCO-S	Low-speed on-chip oscillator frequency		30	125	250	kHz
—	Oscillation stability time		—	10	100	μs
—	Self power consumption at oscillation	VCC = 5.0 V, Topr = 25°C	—	15	—	μA

## NOTE:

1. VCC = 2.2 to 5.5 V, Topr = -20 to 85°C (N version) / -40 to 85°C (D version), unless otherwise specified.

**Table 5.12 Power Supply Circuit Timing Characteristics**

Symbol	Parameter	Condition	Standard			Unit
			Min.	Typ.	Max.	
td(P-R)	Time for internal power supply stabilization during power-on <sup>(2)</sup>		1	—	2000	μs
td(R-S)	STOP exit time <sup>(3)</sup>		—	—	150	μs

## NOTES:

1. The measurement condition is VCC = 2.2 to 5.5 V and Topr = 25°C.
2. Waiting time until the internal power supply generation circuit stabilizes during power-on.
3. Time until system clock supply starts after the interrupt is acknowledged to exit stop mode.



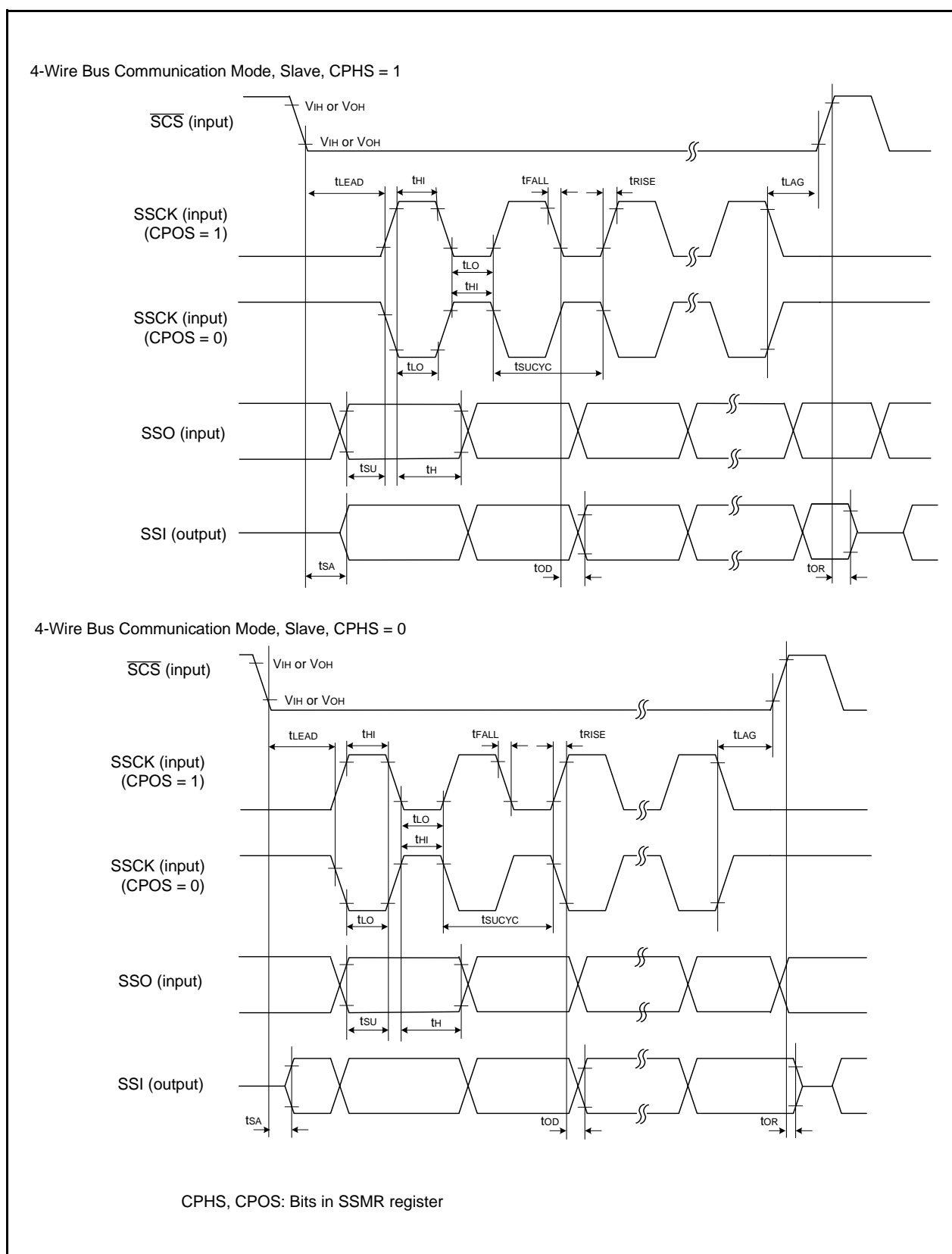


Figure 5.5 I/O Timing of Clock Synchronous Serial I/O with Chip Select (Slave)

**Table 5.15 Electrical Characteristics (1) [V<sub>CC</sub> = 5 V]**

Symbol	Parameter		Condition	Standard			Unit
				Min.	Typ.	Max.	
V <sub>OH</sub>	Output "H" voltage	Except P1_0 to P1_7, XOUT	I <sub>OH</sub> = -5 mA	V <sub>CC</sub> - 2.0	—	V <sub>CC</sub>	V
			I <sub>OH</sub> = -200 $\mu$ A	V <sub>CC</sub> - 0.5	—	V <sub>CC</sub>	V
		P1_0 to P1_7	Drive capacity HIGH I <sub>OH</sub> = -20 mA	V <sub>CC</sub> - 2.0	—	V <sub>CC</sub>	V
			Drive capacity LOW I <sub>OH</sub> = -5 mA	V <sub>CC</sub> - 2.0	—	V <sub>CC</sub>	V
		XOUT	Drive capacity HIGH I <sub>OH</sub> = -1 mA	V <sub>CC</sub> - 2.0	—	V <sub>CC</sub>	V
			Drive capacity LOW I <sub>OH</sub> = -500 $\mu$ A	V <sub>CC</sub> - 2.0	—	V <sub>CC</sub>	V
V <sub>OL</sub>	Output "L" voltage	Except P1_0 to P1_7, XOUT	I <sub>OL</sub> = 5 mA	—	—	2.0	V
			I <sub>OL</sub> = 200 $\mu$ A	—	—	0.45	V
		P1_0 to P1_7	Drive capacity HIGH I <sub>OL</sub> = 20 mA	—	—	2.0	V
			Drive capacity LOW I <sub>OL</sub> = 5 mA	—	—	2.0	V
		XOUT	Drive capacity HIGH I <sub>OL</sub> = 1 mA	—	—	2.0	V
			Drive capacity LOW I <sub>OL</sub> = 500 $\mu$ A	—	—	2.0	V
V <sub>T+</sub> -V <sub>T-</sub>	Hysteresis	INT0, INT1, INT3, KI0, KI1, KI2, KI3, TRAIO, RXD0, RXD1, CLK0, SSI, SCL, SDA, SSO		0.1	0.5	—	V
		RESET		0.1	1.0	—	V
I <sub>IH</sub>	Input "H" current		V <sub>I</sub> = 5 V, V <sub>CC</sub> = 5V	—	—	5.0	$\mu$ A
I <sub>IL</sub>	Input "L" current		V <sub>I</sub> = 0 V, V <sub>CC</sub> = 5V	—	—	-5.0	$\mu$ A
R <sub>PULLUP</sub>	Pull-up resistance		V <sub>I</sub> = 0 V, V <sub>CC</sub> = 5V	30	50	167	k $\Omega$
R <sub>IXIN</sub>	Feedback resistance	XIN		—	1.0	—	M $\Omega$
R <sub>IXCIN</sub>	Feedback resistance	XCIN		—	18	—	M $\Omega$
V <sub>RAM</sub>	RAM hold voltage		During stop mode	1.8	—	—	V

## NOTE:

- V<sub>CC</sub> = 4.2 to 5.5 V at T<sub>opr</sub> = -20 to 85°C (N version) / -40 to 85°C (D version), f(XIN) = 20 MHz, unless otherwise specified.

**Table 5.17 Electrical Characteristics (3) [Vcc = 5 V]**  
**(T<sub>opr</sub> = -20 to 85°C (N version) / -40 to 85°C (D version), unless otherwise specified.)**

Symbol	Parameter	Condition	Standard			Unit	
			Min.	Typ.	Max.		
Icc	Power supply current (Vcc = 3.3 to 5.5 V) Single-chip mode, output pins are open, other pins are Vss	Wait mode	XIN clock off High-speed on-chip oscillator off Low-speed on-chip oscillator on = 125 kHz While a WAIT instruction is executed Peripheral clock operation VCA27 = VCA26 = VCA25 = 0 VCA20 = 1	–	25	75	μA
			XIN clock off High-speed on-chip oscillator off Low-speed on-chip oscillator on = 125 kHz While a WAIT instruction is executed Peripheral clock off VCA27 = VCA26 = VCA25 = 0 VCA20 = 1	–	23	60	μA
			XIN clock off High-speed on-chip oscillator off Low-speed on-chip oscillator off XCIN clock oscillator on = 32 kHz (high drive) While a WAIT instruction is executed VCA27 = VCA26 = VCA25 = 0 VCA20 = 1	–	4.0	–	μA
			XIN clock off High-speed on-chip oscillator off Low-speed on-chip oscillator off XCIN clock oscillator on = 32 kHz (low drive) While a WAIT instruction is executed VCA27 = VCA26 = VCA25 = 0 VCA20 = 1	–	2.2	–	μA
		Stop mode	XIN clock off, Topr = 25°C High-speed on-chip oscillator off Low-speed on-chip oscillator off CM10 = 1 Peripheral clock off VCA27 = VCA26 = VCA25 = 0	–	0.8	3.0	μA
			XIN clock off, Topr = 85°C High-speed on-chip oscillator off Low-speed on-chip oscillator off CM10 = 1 Peripheral clock off VCA27 = VCA26 = VCA25 = 0	–	1.2	–	μA

**Table 5.22 Electrical Characteristics (3) [V<sub>CC</sub> = 3 V]**

Symbol	Parameter		Condition		Standard			Unit
					Min.	Typ.	Max.	
V <sub>OH</sub>	Output "H" voltage	Except P1_0 to P1_7, XOUT	I <sub>OH</sub> = -1 mA		V <sub>CC</sub> - 0.5	—	V <sub>CC</sub>	V
		P1_0 to P1_7	Drive capacity HIGH	I <sub>OH</sub> = -5 mA	V <sub>CC</sub> - 0.5	—	V <sub>CC</sub>	V
			Drive capacity LOW	I <sub>OH</sub> = -1 mA	V <sub>CC</sub> - 0.5	—	V <sub>CC</sub>	V
		XOUT	Drive capacity HIGH	I <sub>OH</sub> = -0.1 mA	V <sub>CC</sub> - 0.5	—	V <sub>CC</sub>	V
			Drive capacity LOW	I <sub>OH</sub> = -50 μA	V <sub>CC</sub> - 0.5	—	V <sub>CC</sub>	V
V <sub>OL</sub>	Output "L" voltage	Except P1_0 to P1_7, XOUT	I <sub>OL</sub> = 1 mA		—	—	0.5	V
		P1_0 to P1_7	Drive capacity HIGH	I <sub>OL</sub> = 5 mA	—	—	0.5	V
			Drive capacity LOW	I <sub>OL</sub> = 1 mA	—	—	0.5	V
		XOUT	Drive capacity HIGH	I <sub>OL</sub> = 0.1 mA	—	—	0.5	V
			Drive capacity LOW	I <sub>OL</sub> = 50 μA	—	—	0.5	V
V <sub>T+</sub> -V <sub>T-</sub>	Hysteresis	INT0, INT1, INT3, KI0, KI1, KI2, KI3, TRAIO, RXD0, RXD1, CLK0, SSI, SCL, SDA, SSO			0.1	0.3	—	V
		RESET			0.1	0.4	—	V
I <sub>IH</sub>	Input "H" current		V <sub>I</sub> = 3 V, V <sub>CC</sub> = 3V		—	—	4.0	μA
I <sub>IL</sub>	Input "L" current		V <sub>I</sub> = 0 V, V <sub>CC</sub> = 3V		—	—	-4.0	μA
R <sub>PULLUP</sub>	Pull-up resistance		V <sub>I</sub> = 0 V, V <sub>CC</sub> = 3V		66	160	500	kΩ
R <sub>FXIN</sub>	Feedback resistance	XIN			—	3.0	—	MΩ
R <sub>FXCIN</sub>	Feedback resistance	XCIN			—	18	—	MΩ
V <sub>RAM</sub>	RAM hold voltage		During stop mode		1.8	—	—	V

**NOTE:**

- V<sub>CC</sub> = 2.7 to 3.3 V at T<sub>opr</sub> = -20 to 85°C (N version) / -40 to 85°C (D version), f(XIN) = 10 MHz, unless otherwise specified.

**Table 5.23 Electrical Characteristics (4) [V<sub>CC</sub> = 3 V]**  
**(T<sub>opr</sub> = -20 to 85°C (N version) / -40 to 85°C (D version), unless otherwise specified.)**

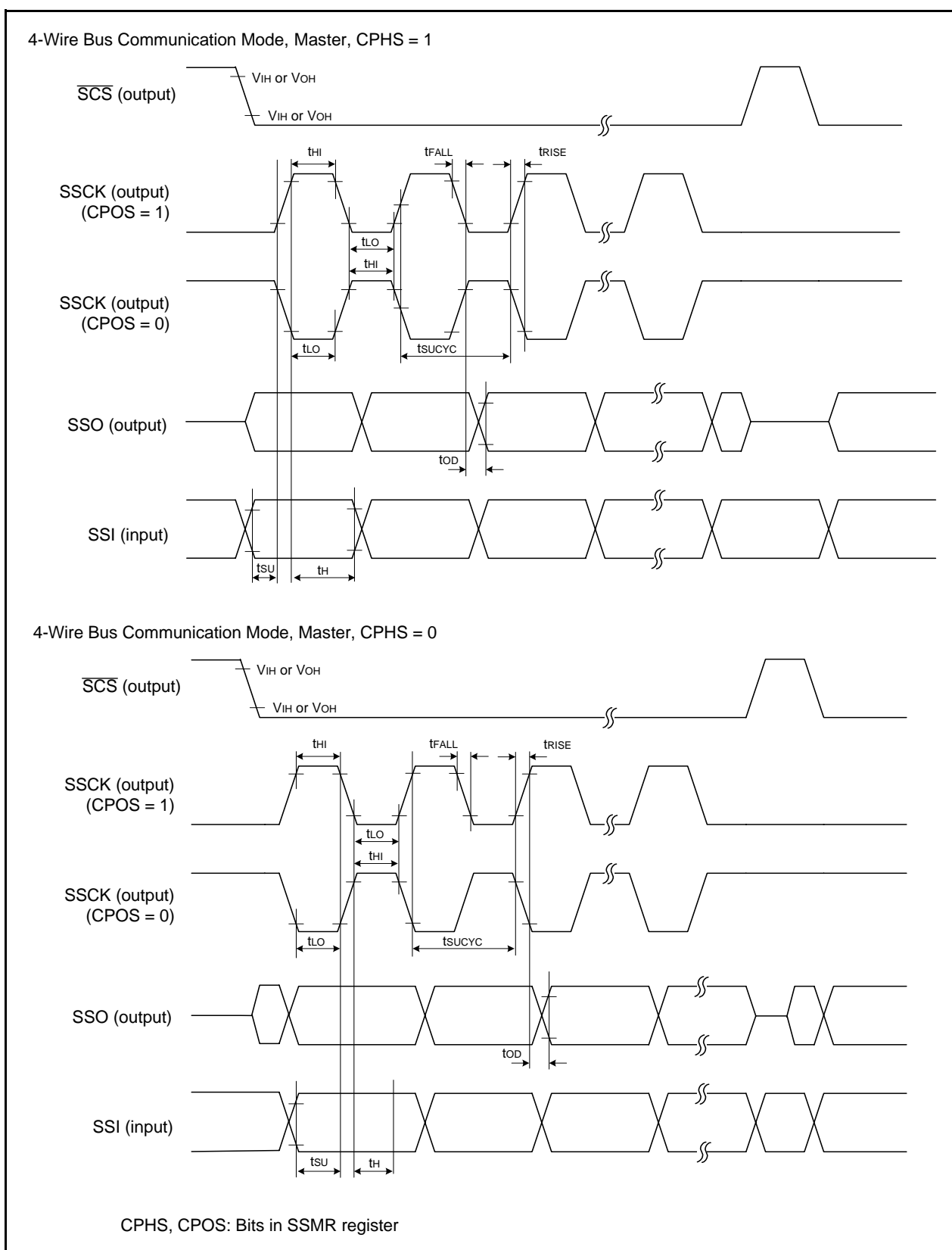
Symbol	Parameter	Condition	Standard			Unit
			Min.	Typ.	Max.	
I <sub>CC</sub>	Power supply current (V <sub>CC</sub> = 2.7 to 3.3 V) Single-chip mode, output pins are open, other pins are V <sub>SS</sub>	High-speed clock mode	XIN = 10 MHz (square wave) High-speed on-chip oscillator off Low-speed on-chip oscillator on = 125 kHz No division			mA
			XIN = 10 MHz (square wave) High-speed on-chip oscillator off Low-speed on-chip oscillator on = 125 kHz Divide-by-8			mA
		High-speed on-chip oscillator mode	XIN clock off High-speed on-chip oscillator on f <sub>OCO</sub> = 10 MHz Low-speed on-chip oscillator on = 125 kHz No division			mA
			XIN clock off High-speed on-chip oscillator on f <sub>OCO</sub> = 10 MHz Low-speed on-chip oscillator on = 125 kHz Divide-by-8			mA
		Low-speed on-chip oscillator mode	XIN clock off High-speed on-chip oscillator off Low-speed on-chip oscillator on = 125 kHz Divide-by-8, FMR47 = 1			μA
		Low-speed clock mode	XIN clock off High-speed on-chip oscillator off Low-speed on-chip oscillator off XCIN clock oscillator on = 32 kHz FMR47 = 1			μA
			XIN clock off High-speed on-chip oscillator off Low-speed on-chip oscillator off XCIN clock oscillator on = 32 kHz Program operation on RAM Flash memory off, FMSTP = 1			μA
		Wait mode	XIN clock off High-speed on-chip oscillator off Low-speed on-chip oscillator on = 125 kHz While a WAIT instruction is executed Peripheral clock operation VCA27 = VCA26 = VCA25 = 0 VCA20 = 1			μA
			XIN clock off High-speed on-chip oscillator off Low-speed on-chip oscillator on = 125 kHz While a WAIT instruction is executed Peripheral clock off VCA27 = VCA26 = VCA25 = 0 VCA20 = 1			μA
			XIN clock off High-speed on-chip oscillator off Low-speed on-chip oscillator off XCIN clock oscillator on = 32 kHz (high drive) While a WAIT instruction is executed VCA27 = VCA26 = VCA25 = 0 VCA20 = 1			μA
			XIN clock off High-speed on-chip oscillator off Low-speed on-chip oscillator off XCIN clock oscillator on = 32 kHz (low drive) While a WAIT instruction is executed VCA27 = VCA26 = VCA25 = 0 VCA20 = 1			μA
			XIN clock off, T <sub>opr</sub> = 25°C High-speed on-chip oscillator off Low-speed on-chip oscillator off CM10 = 1 Peripheral clock off VCA27 = VCA26 = VCA25 = 0			μA
		Stop mode	XIN clock off, T <sub>opr</sub> = 85°C High-speed on-chip oscillator off Low-speed on-chip oscillator off CM10 = 1 Peripheral clock off VCA27 = VCA26 = VCA25 = 0			μA

**Table 5.37 Flash Memory (Program ROM) Electrical Characteristics**

Symbol	Parameter	Conditions	Standard			Unit
			Min.	Typ.	Max.	
–	Program/erase endurance <sup>(2)</sup>	R8C/28 Group	100 <sup>(3)</sup>	–	–	times
		R8C/29 Group	1,000 <sup>(3)</sup>	–	–	times
–	Byte program time		–	50	400	μs
–	Block erase time		–	0.4	9	s
t <sub>d</sub> (SR-SUS)	Time delay from suspend request until suspend		–	–	97 + CPU clock × 6 cycles	μs
–	Interval from erase start/restart until following suspend request		650	–	–	μs
–	Interval from program start/restart until following suspend request		0	–	–	ns
–	Time from suspend until program/erase restart		–	–	3 + CPU clock × 4 cycles	μs
–	Program, erase voltage		2.7	–	5.5	V
–	Read voltage		2.7	–	5.5	V
–	Program, erase temperature		0	–	60	°C
–	Data hold time <sup>(7)</sup>	Ambient temperature = 55°C	20	–	–	year

**NOTES:**

1. V<sub>CC</sub> = 2.7 to 5.5 V at T<sub>opr</sub> = 0 to 60°C, unless otherwise specified.
2. Definition of programming/erasure endurance  
The programming and erasure endurance is defined on a per-block basis.  
If the programming and erasure endurance is n (n = 100 or 1,000), each block can be erased n times. For example, if 1,024 1-byte writes are performed to different addresses in block A, a 1 Kbyte block, and then the block is erased, the programming/erasure endurance still stands at one.  
However, the same address must not be programmed more than once per erase operation (overwriting prohibited).
3. Endurance to guarantee all electrical characteristics after program and erase. (1 to Min. value can be guaranteed).
4. In a system that executes multiple programming operations, the actual erasure count can be reduced by writing to sequential addresses in turn so that as much of the block as possible is used up before performing an erase operation. For example, when programming groups of 16 bytes, the effective number of rewrites can be minimized by programming up to 128 groups before erasing them all in one operation. It is also advisable to retain data on the erasure endurance of each block and limit the number of erase operations to a certain number.
5. If an error occurs during block erase, attempt to execute the clear status register command, then execute the block erase command at least three times until the erase error does not occur.
6. Customers desiring program/erase failure rate information should contact their Renesas technical support representative.
7. The data hold time includes time that the power supply is off or the clock is not supplied.



**Figure 5.23** I/O Timing of Clock Synchronous Serial I/O with Chip Select (Master)

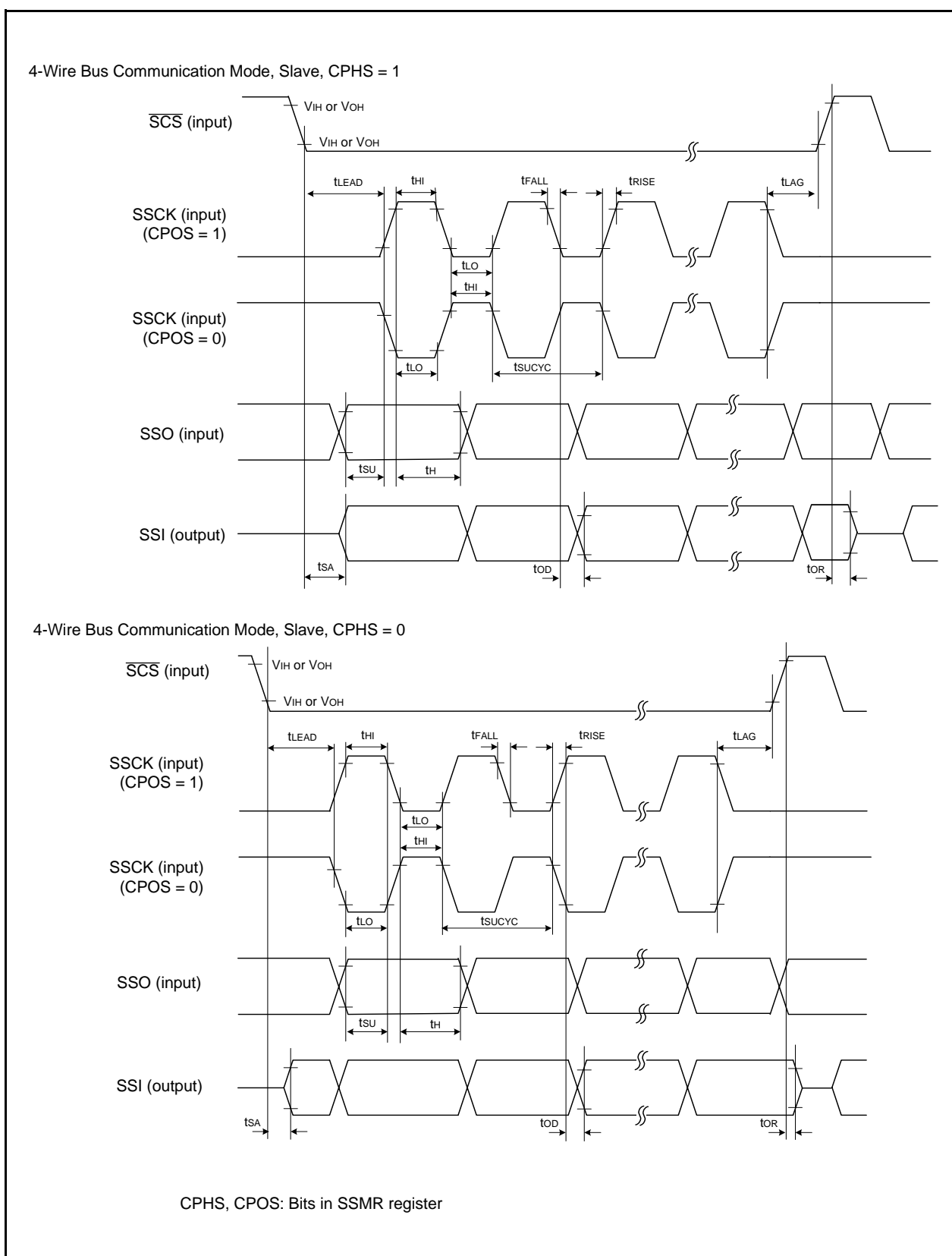


Figure 5.24 I/O Timing of Clock Synchronous Serial I/O with Chip Select (Slave)

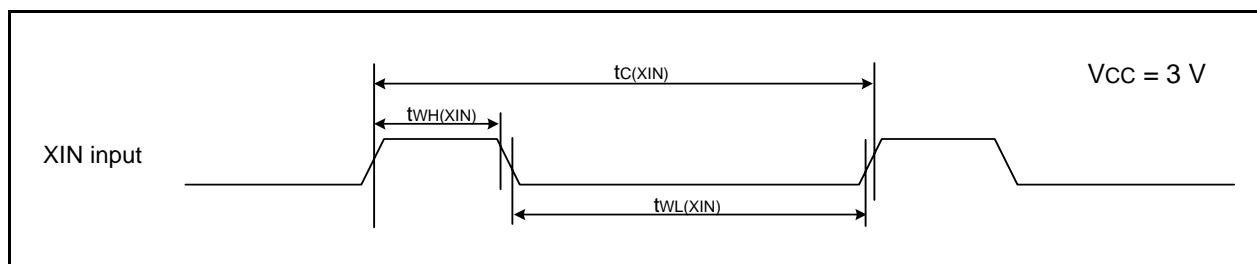


**Table 5.48 Electrical Characteristics (2) [V<sub>CC</sub> = 5 V]**  
**(T<sub>opr</sub> = -40 to 85°C (J version) / -40 to 125°C (K version), unless otherwise specified.)**

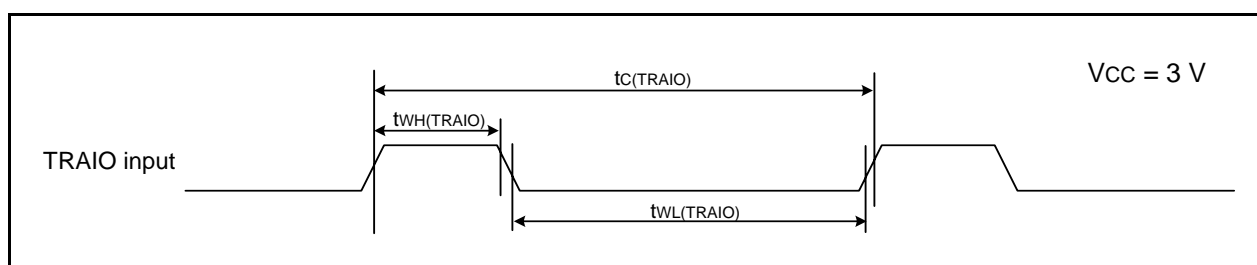
Symbol	Parameter	Condition			Standard			Unit
					Min.	Typ.	Max.	
Icc	Power supply current (Vcc = 3.3 to 5.5 V) Single-chip mode, output pins are open, other pins are Vss	High-speed clock mode	XIN = 20 MHz (square wave) High-speed on-chip oscillator off Low-speed on-chip oscillator on = 125 kHz No division	—	10	17	mA	
			XIN = 16 MHz (square wave) High-speed on-chip oscillator off Low-speed on-chip oscillator on = 125 kHz No division	—	9	15	mA	
			XIN = 10 MHz (square wave) High-speed on-chip oscillator off Low-speed on-chip oscillator on = 125 kHz No division	—	6	—	mA	
			XIN = 20 MHz (square wave) High-speed on-chip oscillator off Low-speed on-chip oscillator on = 125 kHz Divide-by-8	—	5	—	mA	
			XIN = 16 MHz (square wave) High-speed on-chip oscillator off Low-speed on-chip oscillator on = 125 kHz Divide-by-8	—	4	—	mA	
			XIN = 10 MHz (square wave) High-speed on-chip oscillator off Low-speed on-chip oscillator on = 125 kHz Divide-by-8	—	2.5	—	mA	
		High-speed on-chip oscillator mode	XIN clock off High-speed on-chip oscillator on fOCO = 20 MHz (J version) Low-speed on-chip oscillator on = 125 kHz No division	—	10	15	mA	
			XIN clock off High-speed on-chip oscillator on fOCO = 20 MHz (J version) Low-speed on-chip oscillator on = 125 kHz Divide-by-8	—	4	—	mA	
			XIN clock off High-speed on-chip oscillator on fOCO = 10 MHz Low-speed on-chip oscillator on = 125 kHz No division	—	5.5	10	mA	
			XIN clock off High-speed on-chip oscillator on fOCO = 10 MHz Low-speed on-chip oscillator on = 125 kHz Divide-by-8	—	2.5	—	mA	
		Low-speed on-chip oscillator mode	XIN clock off High-speed on-chip oscillator off Low-speed on-chip oscillator on = 125 kHz Divide-by-8, FMR47 = 1	—	130	300	μA	
		Wait mode	XIN clock off High-speed on-chip oscillator off Low-speed on-chip oscillator on = 125 kHz While a WAIT instruction is executed Peripheral clock operation VCA27 = VCA26 = VCA25 = 0 VCA20 = 1	—	25	75	μA	
			XIN clock off High-speed on-chip oscillator off Low-speed on-chip oscillator on = 125 kHz While a WAIT instruction is executed Peripheral clock off VCA27 = VCA26 = VCA25 = 0 VCA20 = 1	—	23	60	μA	
		Stop mode	XIN clock off, Topr = 25°C High-speed on-chip oscillator off Low-speed on-chip oscillator off CM10 = 1 Peripheral clock off VCA27 = VCA26 = VCA25 = 0	—	0.8	3.0	μA	
			XIN clock off, Topr = 85°C High-speed on-chip oscillator off Low-speed on-chip oscillator off CM10 = 1 Peripheral clock off VCA27 = VCA26 = VCA25 = 0	—	1.2	—	μA	
			XIN clock off, Topr = 125°C High-speed on-chip oscillator off Low-speed on-chip oscillator off CM10 = 1 Peripheral clock off VCA27 = VCA26 = VCA25 = 0	—	4.0	—	μA	

**Timing requirements****(Unless Otherwise Specified:  $V_{CC} = 3\text{ V}$ ,  $V_{SS} = 0\text{ V}$  at  $T_{opr} = 25^{\circ}\text{C}$ ) [ $V_{CC} = 3\text{ V}$ ]****Table 5.55 XIN Input**

Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_{c(XIN)}$	XIN input cycle time	100	–	ns
$t_{WH(XIN)}$	XIN input "H" width	40	–	ns
$t_{WL(XIN)}$	XIN input "L" width	40	–	ns

**Figure 5.31 XIN Input Timing Diagram when  $V_{CC} = 3\text{ V}$** **Table 5.56 TRAIO Input**

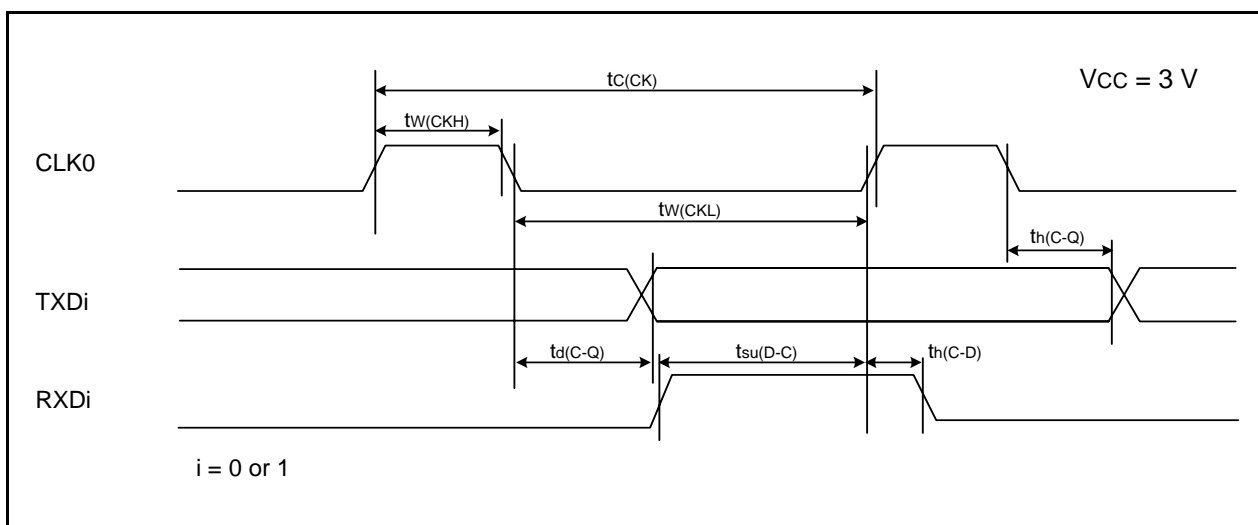
Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_{c(TRAIO)}$	TRAIO input cycle time	300	–	ns
$t_{WH(TRAIO)}$	TRAIO input "H" width	120	–	ns
$t_{WL(TRAIO)}$	TRAIO input "L" width	120	–	ns

**Figure 5.32 TRAIO Input Timing Diagram when  $V_{CC} = 3\text{ V}$**

**Table 5.57 Serial Interface**

Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_{c(CK)}$	CLK0 input cycle time	300	—	ns
$t_{w(CKH)}$	CLK0 input "H" width	150	—	ns
$t_{w(CKL)}$	CLK0 Input "L" width	150	—	ns
$t_{d(C-Q)}$	TXDi output delay time	—	80	ns
$t_{h(C-Q)}$	TXDi hold time	0	—	ns
$t_{su(D-C)}$	RXDi input setup time	70	—	ns
$t_{h(C-D)}$	RXDi input hold time	90	—	ns

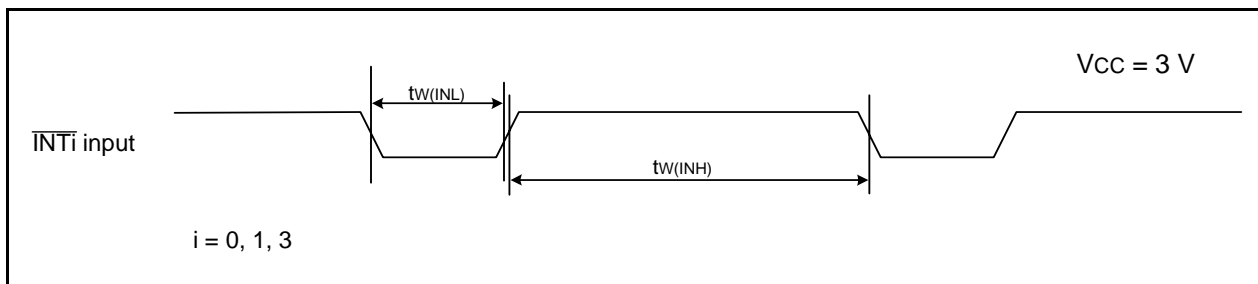
i = 0 or 1

**Figure 5.33 Serial Interface Timing Diagram when Vcc = 3 V****Table 5.58 External Interrupt  $\overline{INTi}$  (i = 0, 1, 3) Input**

Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_{w(INH)}$	$\overline{INTi}$ input "H" width	380 <sup>(1)</sup>	—	ns
$t_{w(INL)}$	$\overline{INTi}$ input "L" width	380 <sup>(2)</sup>	—	ns

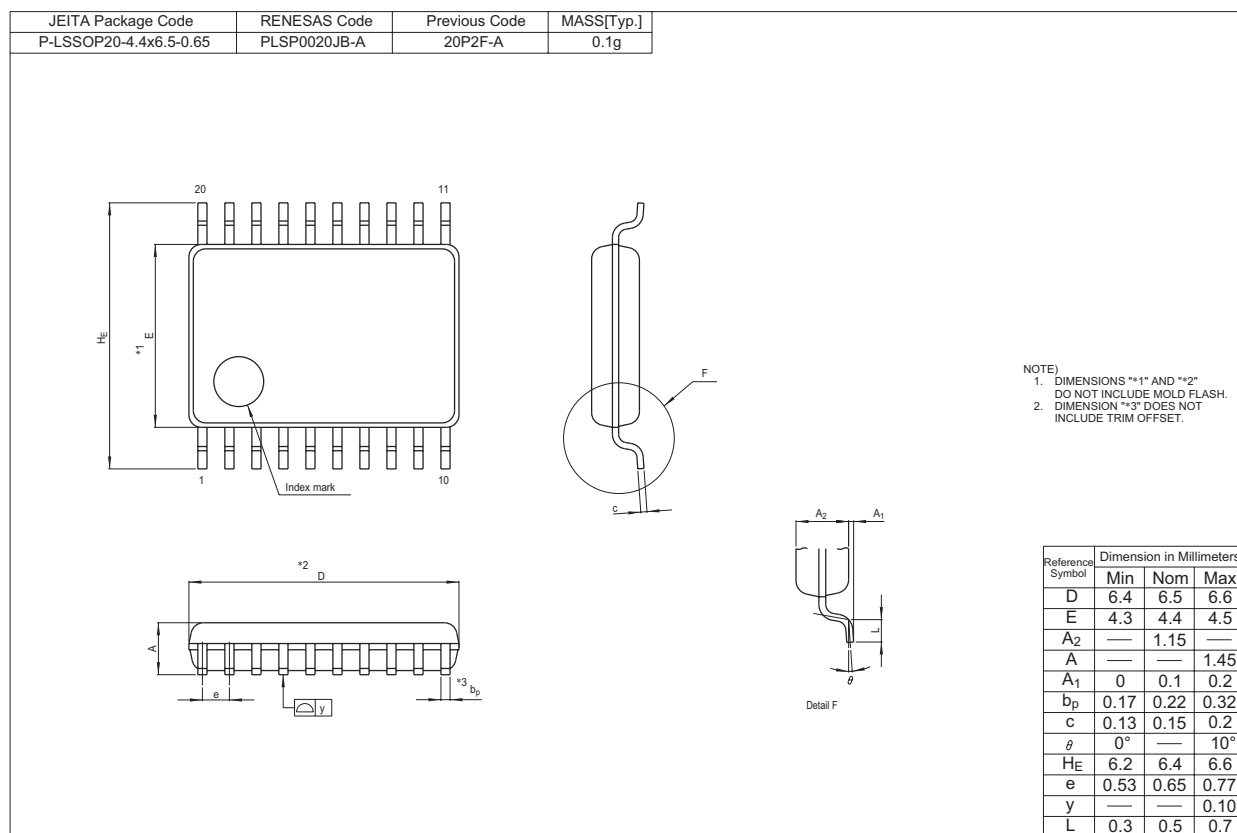
## NOTES:

1. When selecting the digital filter by the  $\overline{INTi}$  input filter select bit, use an  $\overline{INTi}$  input HIGH width of either (1/digital filter clock frequency × 3) or the minimum value of standard, whichever is greater.
2. When selecting the digital filter by the  $\overline{INTi}$  input filter select bit, use an  $\overline{INTi}$  input LOW width of either (1/digital filter clock frequency × 3) or the minimum value of standard, whichever is greater.

**Figure 5.34 External Interrupt  $\overline{INTi}$  Input Timing Diagram when Vcc = 3 V**

## Package Dimensions

Diagrams showing the latest package dimensions and mounting information are available in the “Packages” section of the Renesas Technology website.



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